

6C – RFID Tag Spec

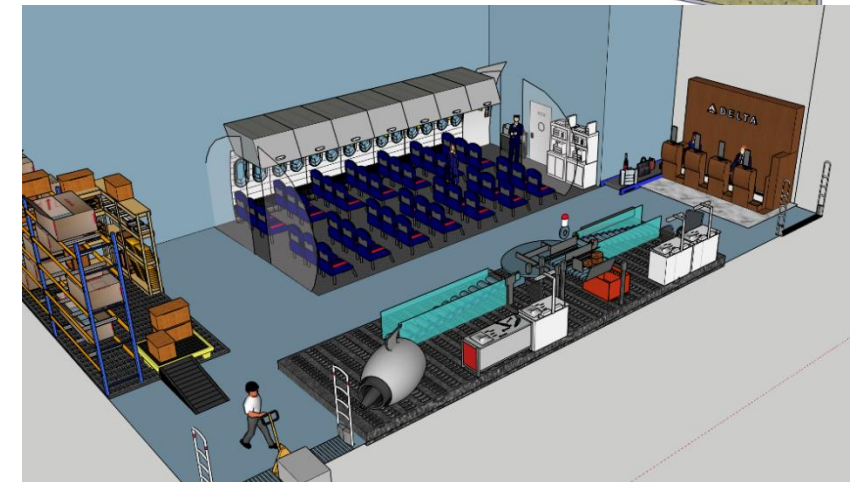
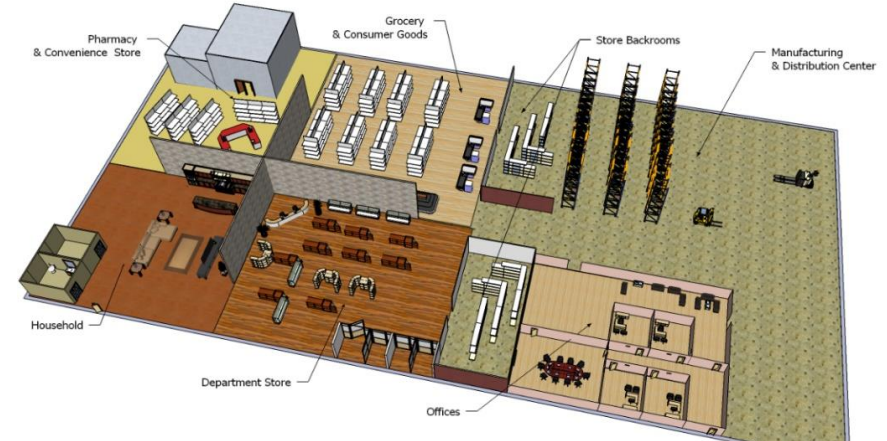


RFID Lab @ Auburn



RFID Lab @ Auburn University

- Focus on business case and value
- 18 years
- Retail, Aerospace, Food, and Logistics
- Education, Research, and Support to enable successful adoption of RFID



RFID Team

- 120 students
 - 15 staff
- Business
 - Engineering
 - Human sciences



ARC Program



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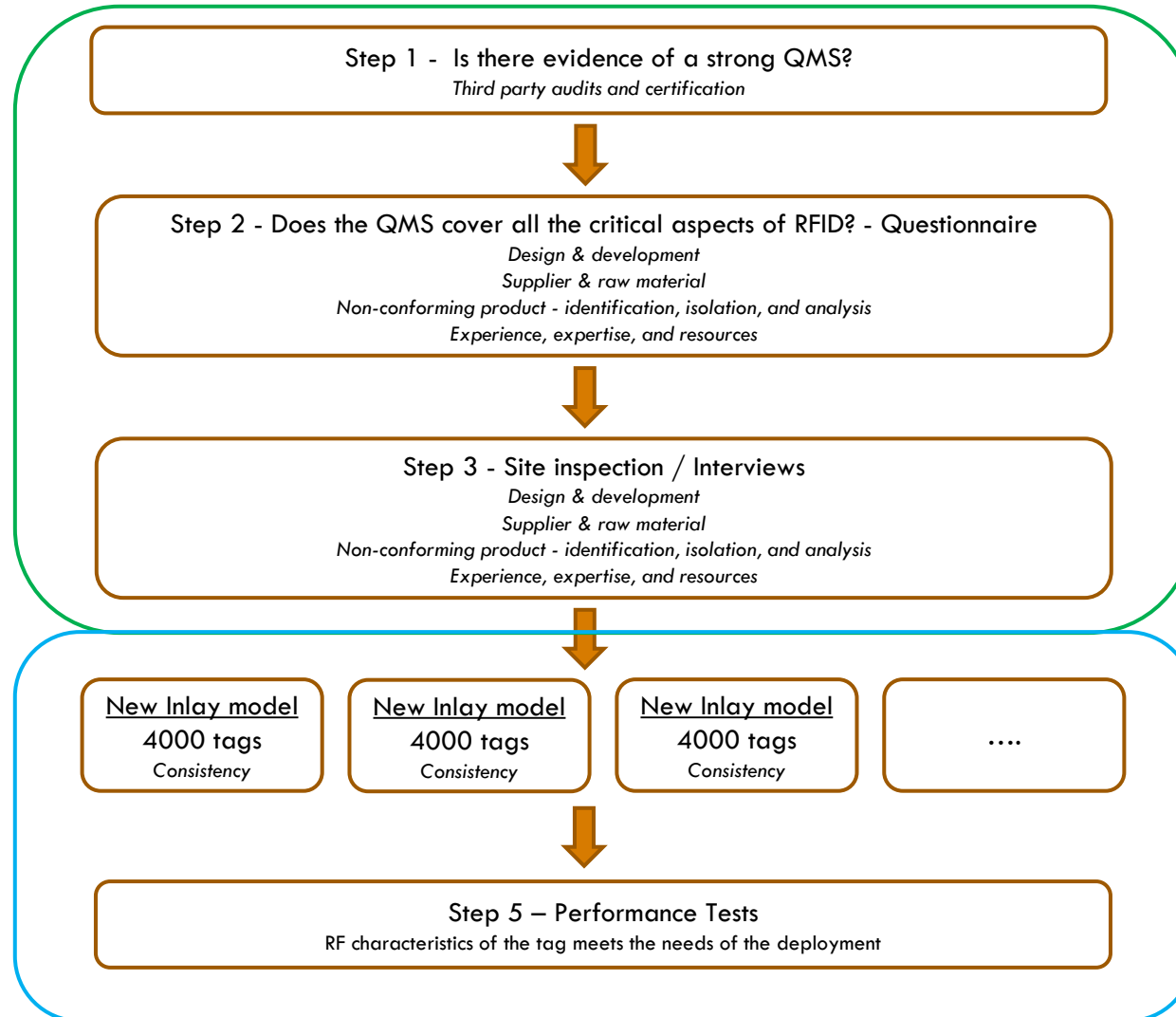
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What is the ARC program?

- Goal – Help end users choose RFID tags that meet the **Performance + Quality + Reliability** requirements of their deployment

ARC Overview



Quality Certification
RFID inlay manufacturer

Performance Certification
RFID inlay model

Tag Quality



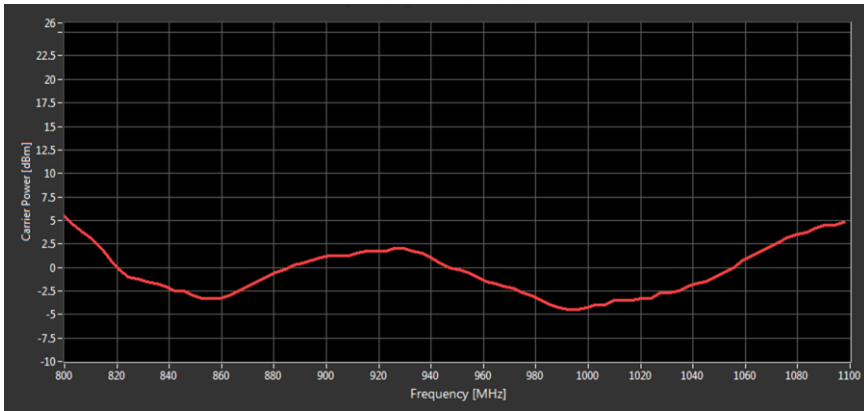
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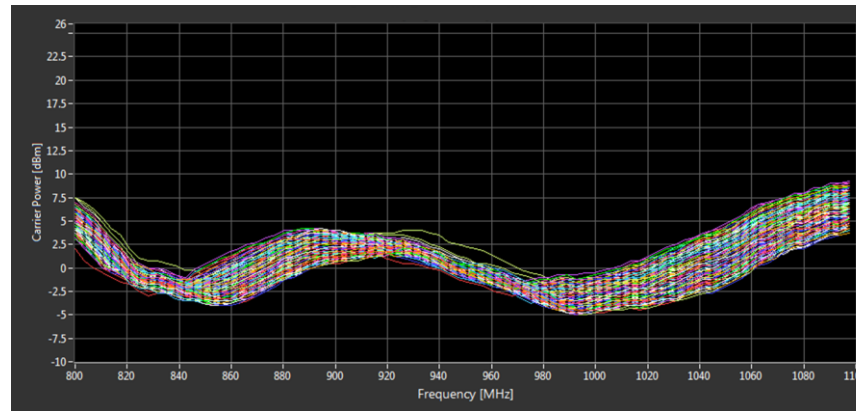
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Tag Quality

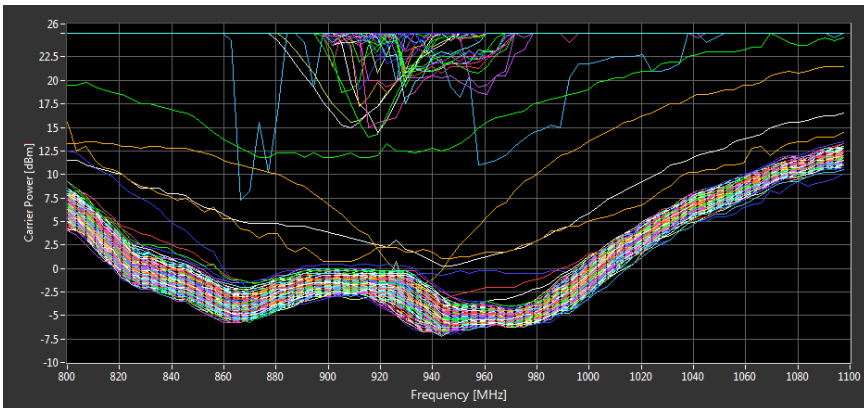
1 Tag



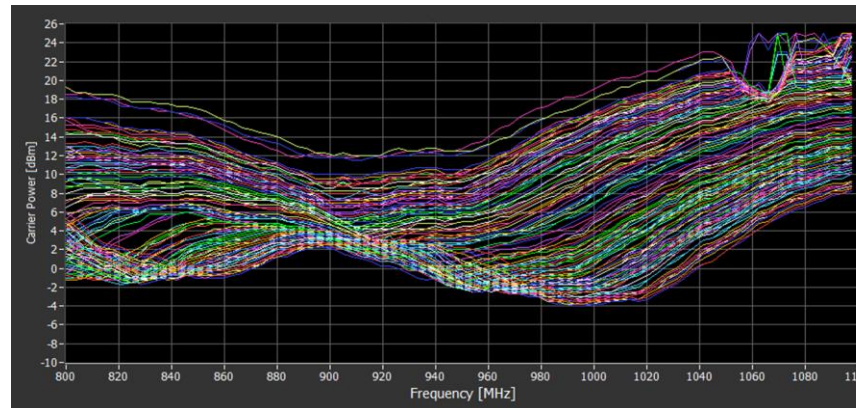
10,000 Tags – Good Quality



10,000 Tags – Bad Quality



10,000 Tags – Bad Quality



Ability to deliver
consistency and reliability
over large volume/time

Tag Quality

- Ensure that RFID tag supplier has Quality Management System that covers the critical aspects of designing and manufacturing of RFID tags
- *Focus areas,*
 - ▣ *Design & development*
 - ▣ *Supplier & raw material*
 - ▣ *Non-conforming product - identification, isolation, and analysis*
 - ▣ *Experience, expertise, and resources*



Tag Performance



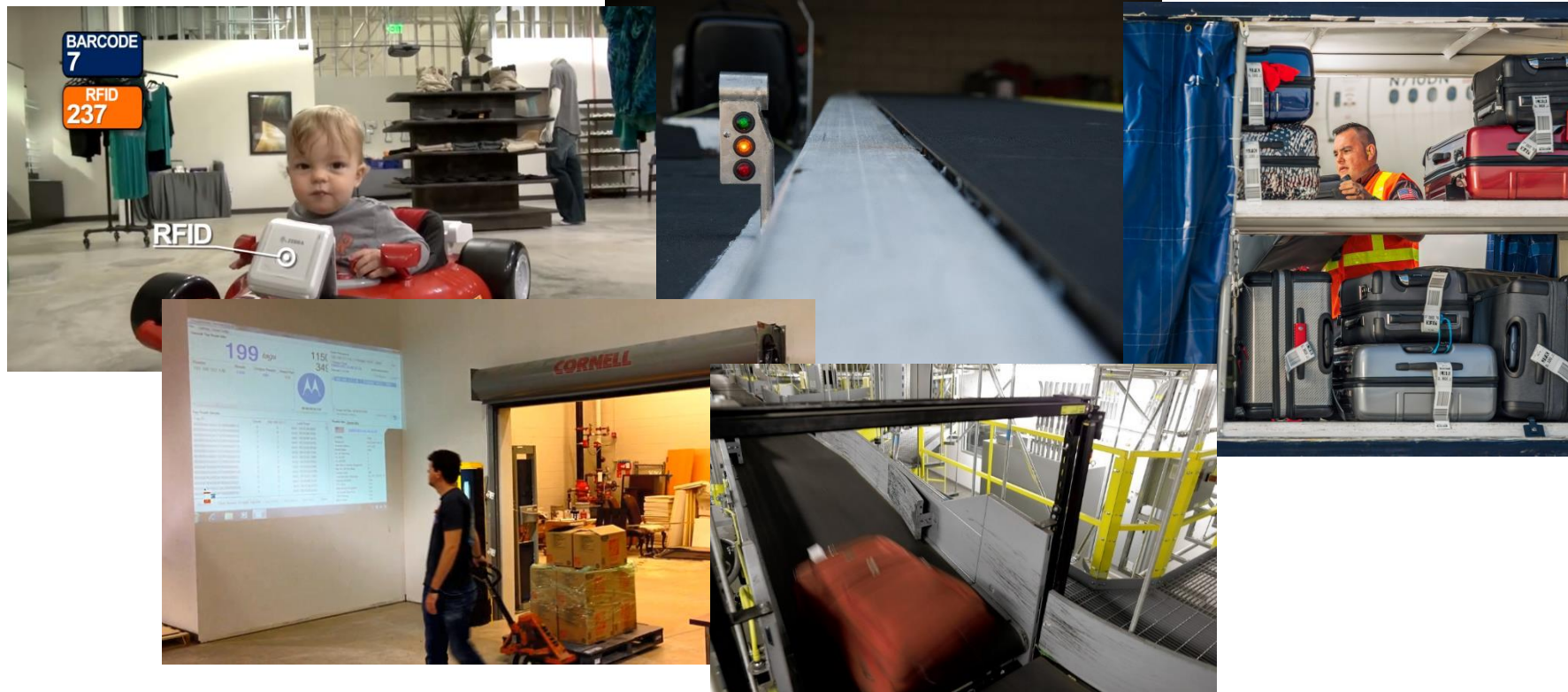
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Tag Performance

- Tag performance is ensuring that we can read the tag reliably when we tried to read them in various scenarios



Tag Performance

Step 1

Identify the requirement
of the deployment
(Spec)



Spec A
Spec B
Spec C
Spec D
Spec F
Spec G
Spec I
Spec K
Spec M
Spec N
Spec Q
Spec U

Tag Performance



Spec J



Tag Database



Step 2

Spec + Tag Database
= Approved Tag list

Approved Inlay List - Spec J

Sort By:

Company
Silicon
Dimension 2

Model
Dimension 1

Company: Avery Dennison
Model: AD-236u7
Silicon: NXP UCODE 7
70 mm x 14.5 mm



Company: Checkpoint
Model: Triumph 2
Silicon: NXP UCODE 7
70 mm x 14 mm



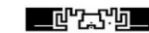
Company: Smartrac
Model: Belt
Silicon: NXP UCODE 8
70 mm x 14 mm



Company: Avery Dennison
Model: AD-385u8
Silicon: NXP UCODE 8
50 mm x 30 mm



Company: SML
Model: MAZE_R6
Silicon: Monza R6
68 mm x 14 mm



Company: Smartrac
Model: Belt
Silicon: NXP UCODE 7
70 mm x 10 mm



Tag Spec for 6C



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Tag Performance

Step 1
Identify the
requirement of the
deployment (Spec)

Tagged Item

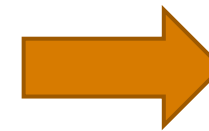
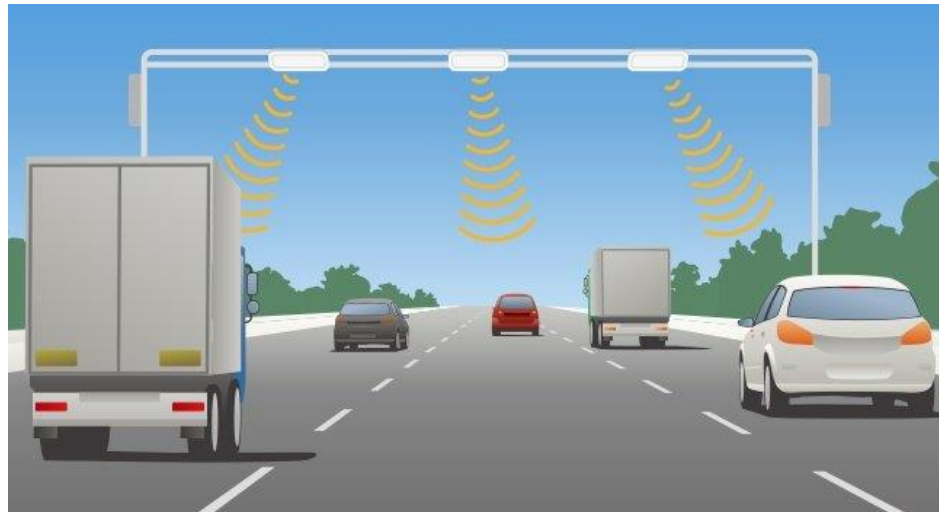
Reader infrastructure

Usecase

Tagging location

Environment

....

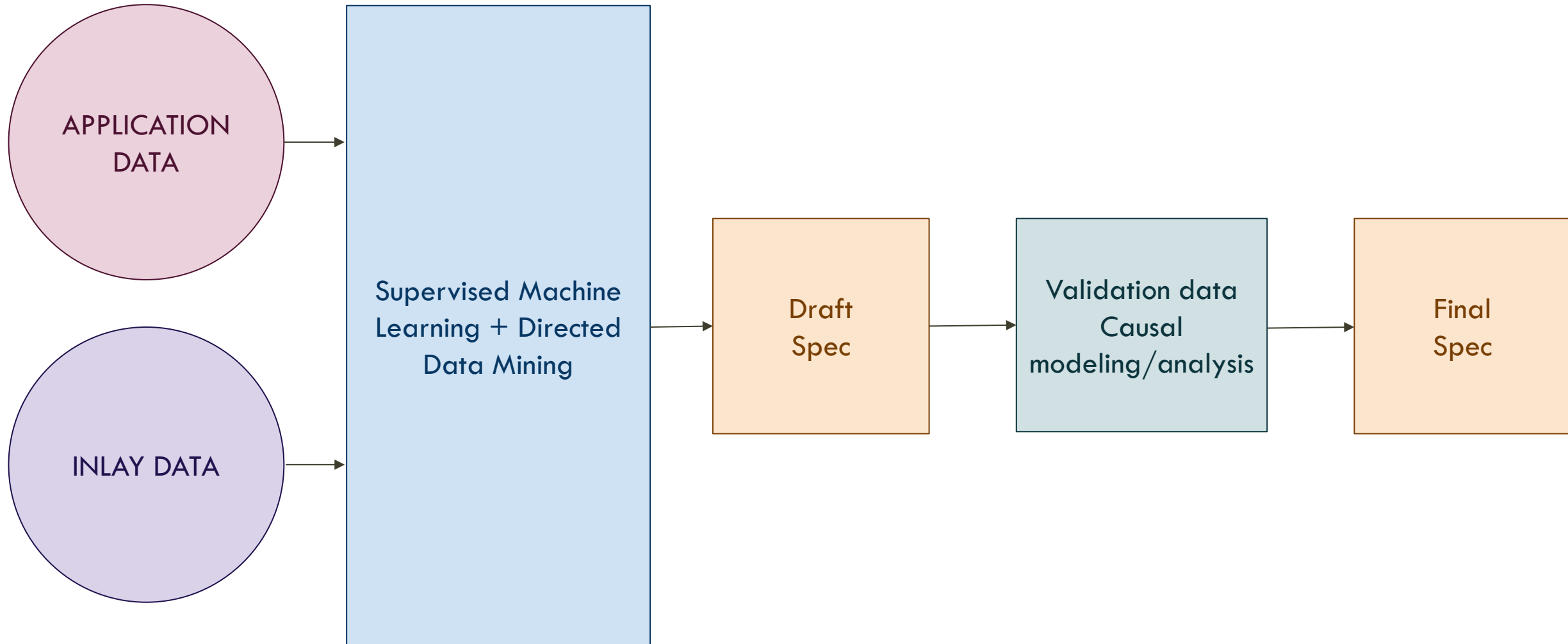


Spec F1
Spec F2
Spec F4



Spec Development Process

Spec Development overview



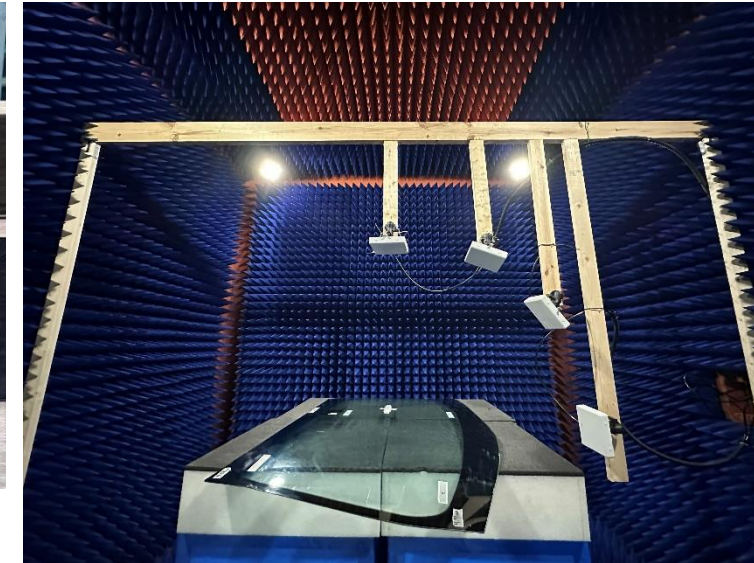
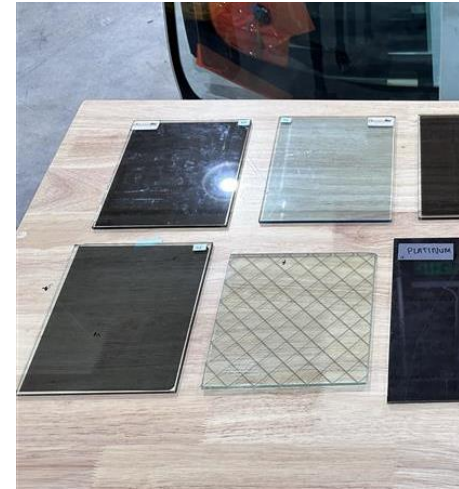
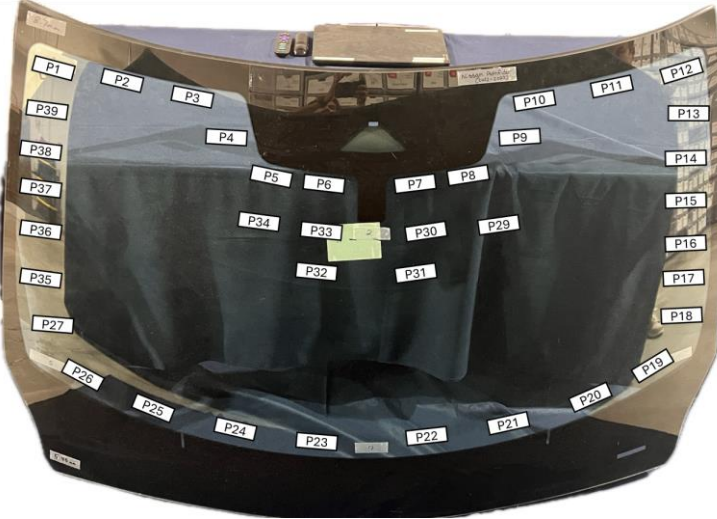
Spec Development overview

APPLICATION
DATA



The first set of data comes from the real-world environment. The goal of this dataset is to capture data from the use case or application. This was achieved by a combination of site visits, interview, survey, and field testing.

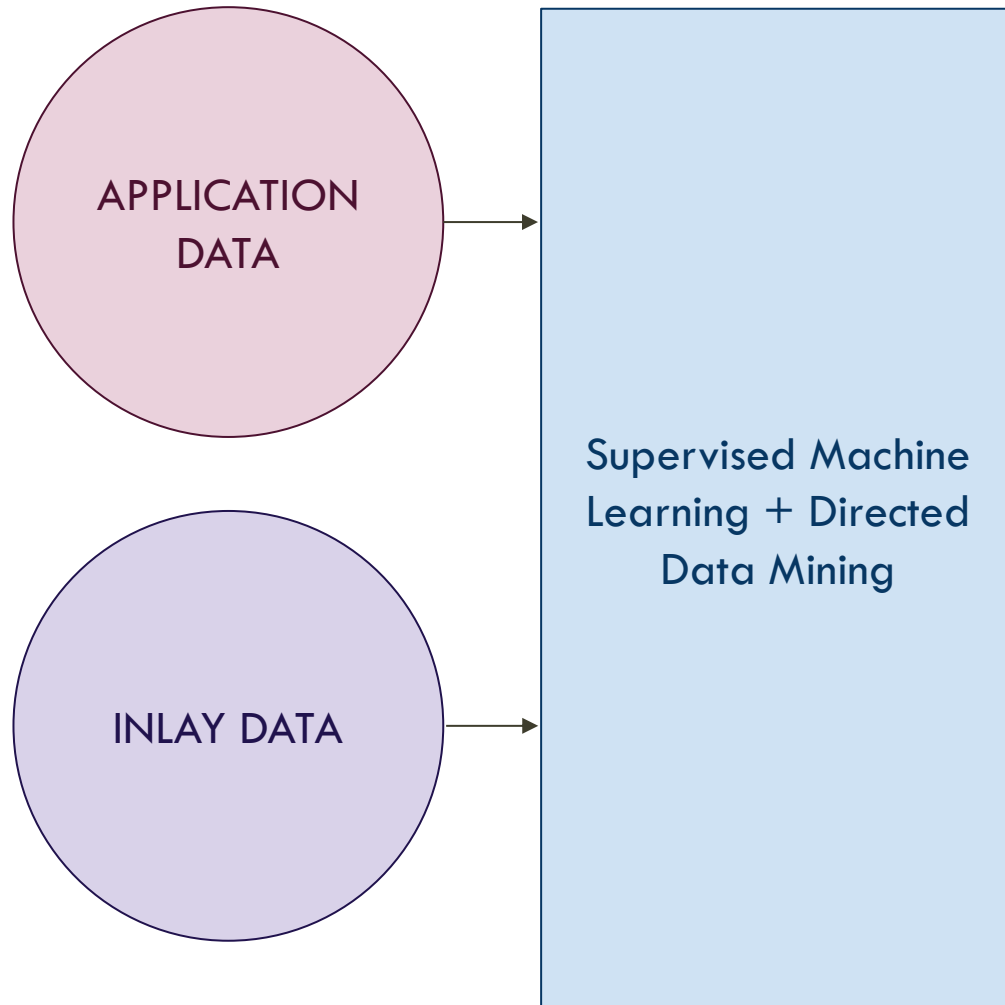
Spec Development overview



INLAY DATA

- The second set of data comes from the anechoic chamber.
- The measurements are taken in multiple different test configurations that cover a range of RF dielectrics and product configurations.
- The test configurations are designed to assess/profile various RF performance characteristics of the tag and tagged products.

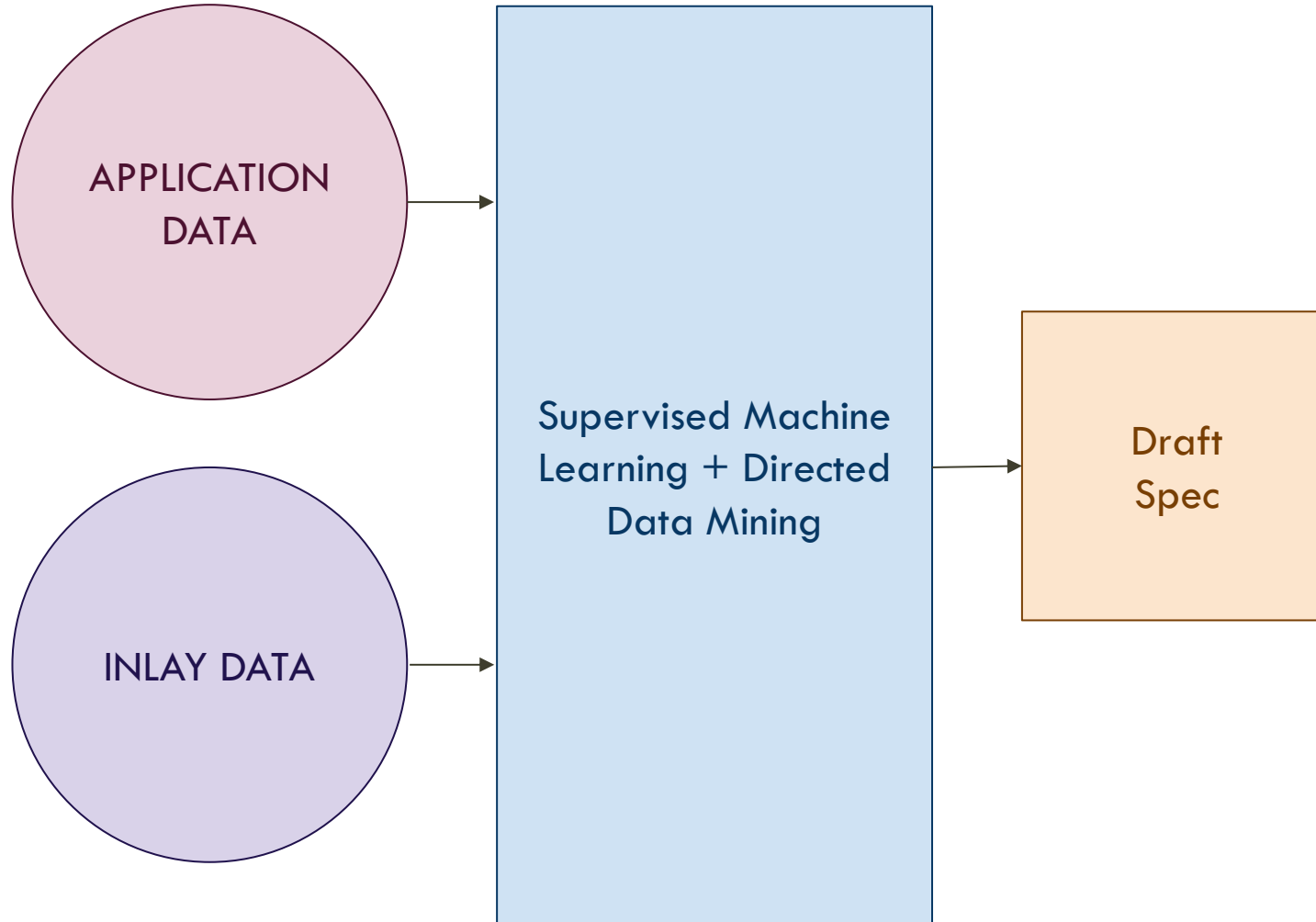
Spec Development overview



Once we have both the datasets, we use we use a combination of supervised-learning and directed data mining to determine which RF performance characteristics of the tag (dataset 2) influence the performance of the tag in the use case (dataset 1).

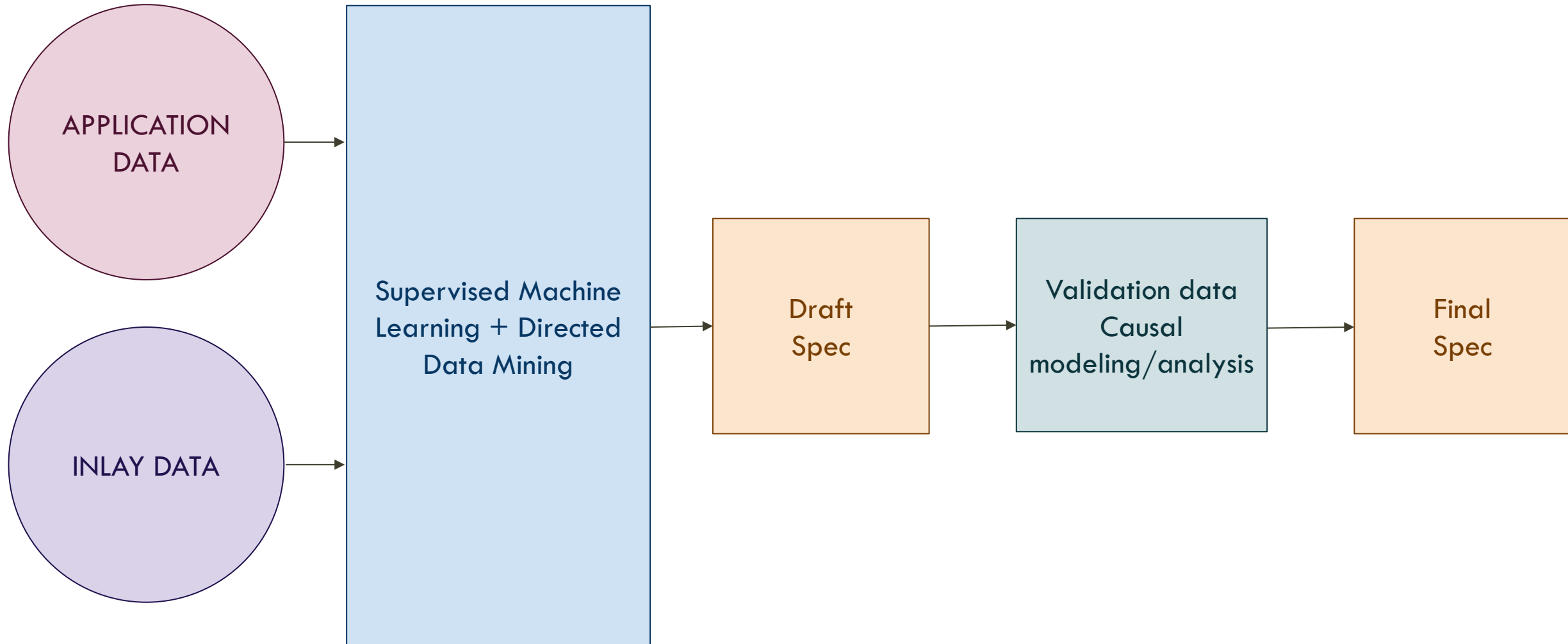
The RF performance characteristics (dataset 2) that predict the performance of the tag in the use case and the metrics behind them (dataset 1) is essentially what becomes the requirements in the Specs.

Spec Development overview



Position 0 Ant 1	Position 0: Ant 2	Position 0: Ant 3	Position 0: Ant 4
-9	-8	-8	-8
Position 30: Ant 1	Position 30: Ant 2	Position 30: Ant 3	Position 30: Ant 4
-7	-6	-6	-5.5
Position 60: Ant 1	Position 60: Ant 2	Position 60: Ant 3	Position 60: Ant 4
-2	NA	NA	NA
Position 120: Ant 1	Position 120: Ant 2	Position 120: Ant 3	Position 120: Ant 4
-2	NA	NA	NA
Position 150: Ant 1	Position 150: Ant 2	Position 150: Ant 3	Position 150: Ant 4
-7	-6	-6	-5.5
Position 180: Ant 1	Position 180: Ant 2	Position 180: Ant 3	Position 180: Ant 4
-9	-8	-8	-8
Position 210: Ant 1	Position 210: Ant 2	Position 210: Ant 3	Position 210: Ant 4
-7	-6	-6	-5.5
Position 240: Ant 1	Position 240: Ant 2	Position 240: Ant 3	Position 240: Ant 4
-2	NA	NA	NA
Position 300: Ant 1	Position 300: Ant 2	Position 300: Ant 3	Position 300: Ant 4
-2	NA	NA	NA
Position 330 Ant 1	Position 330: Ant 2	Position 330: Ant 3	Position 330: Ant 4
-7	-6	-6	-5.5

Spec Development overview



Spec Development overview

- The first dataset that is noisy, uncontrolled, and complex which involves a lot of effort/time/expertise to accurately capture and understand comprehensively.
- The second dataset is standard, accurate, and repeatable.
- The approach we take is to put the initial investment towards understanding the first data, establish the correlation to the second dataset, and then communicate the requirement in the context of the second data set to make the development/validation of tags scalable/accurate.

New Specs

RFID Tag Requirements (Performance, Quality, Reliability)

Spec F1 – Windshield

Spec F2 – Headlight*

Spec F4 – License Plate

RFID Tag Placement Guideline (Draft Template)

ARC Test Methodology**

ARC Test Equipment**

*F1/F2 can be single Spec/Tag. We have separated it if there is a need for separate tags

**Existing Documents

Next steps



- Review and provide comments by Nov 15, 2024
- Publish the Spec to the RFID tag manufacturing community
- RFID Inlay Manufacturers identify/design tags that meet the requirement of the Spec
- Tags sent to Auburn for Certification

Thank you!

arc@rfidlab.org



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